

JAN-28-2004 08:53

WELLS ST. JOHN, P.S.

5098383424 P.07/13
Sheet 1 of 1

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1427		SERIAL NO. 09322,903		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Zhiping Yio et al.				
				FILING DATE April 26, 2000		GROUP 2815		
U.S. PATENT DOCUMENTS								
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
YX	AA	6,111,618	10-2000	Steiner				
	AB	5,994,217	11-1999	Ng				
	AC	5,935,319	11-1999	Kakamu et al.				
	AD	5,747,388	05-1998	Kusters et al.				
	AE	5,639,687	06-1997	Roman et al.				
	AF	5,498,333	03-1996	Lin				
	AG							
	AH							
	AI							
	AJ							
	AK							
	AL							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							
	AP							
	AO							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
YX	AR		Wolf, S. "Silicon Processing for the VLSI Era," Vol. 1, pgs. 417-413.					
YX	AS		Wolf, S. "Silicon Processing for the VLSI Era," Vol. 2, pgs. 48-49 and 435.					
EXAMINER				DATE CONSIDERED				
YX/MS				2/17/04				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

F.T. 979950463

JAN-28-2004 08:55

WELLS ST. JOHN, P.S.

5098383424 P.13/13

Sheet 1 of 1

Form PTO-1440		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M123-1427		SERIAL NO. 09/559,903		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Zhiping Yin et al.		FILING DATE April 26, 2000		
				GROUP 2815				
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
JK	AA	US 2001/0003064 A1	06-2001	Ohno			Dec. 4, 2000	
M	AB	US 2003/0012211 A1	01-2003	Chang et al.			Jul. 3, 2001	
	AC							
	AD							
	AE							
	AF							
	AG							
	AH							
	AI							
	AJ							
	AK							
	AL							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR							
	AS							
EXAMINER		JKS/ha			DATE CONSIDERED 2/17/04			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								